

Phase Control Thyristor

Preliminary Information

DS5830-1.3 June 2008 (LN26204)

FEATURES

- Double Side Cooling
- High Surge Capability

APPLICATIONS

- High Power Drives
- High Voltage Power Supplies
- Static Switches

VOLTAGE RATINGS

Part and Ordering Number	Repetitive Peak Voltages V_{DRM} and V_{RRM} V	Conditions
DCR490J65*	6500	$T_{vj} = -40^{\circ}\text{C}$ to 125°C , $I_{DRM} = I_{RRM} = 100\text{mA}$, $V_{DRM}, V_{RRM} t_p = 10\text{ms}$, $V_{DSM} \text{ \& } V_{RSM} =$ $V_{DRM} \text{ \& } V_{RRM} + 100\text{V}$ respectively
DCR490J60	6000	
DCR490J55	5500	

Lower voltage grades available.

*6200V @ -40°C , 6500V @ 0°C

KEY PARAMETERS

V_{DRM}	6500V
$I_{T(AV)}$	490A
I_{TSM}	6600A
dV/dt^*	1500V/ μs
dI/dt	200A/ μs

* Higher dV/dt selections available

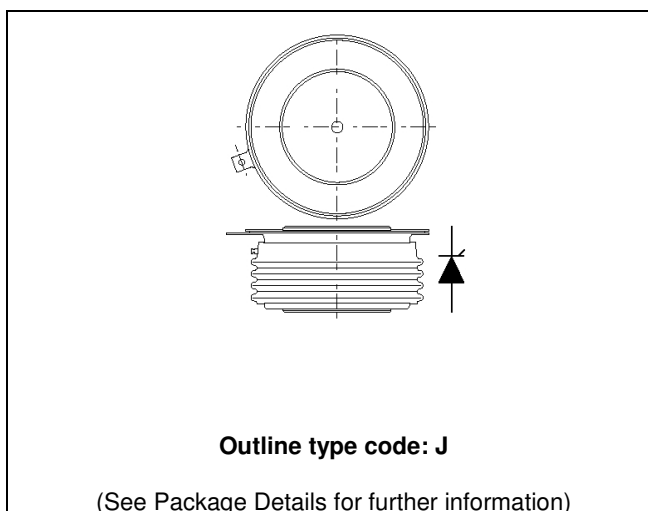


Fig. 1 Package outline

ORDERING INFORMATION

When ordering, select the required part number shown in the Voltage Ratings selection table.

For example:

DCR490J65

Note: Please use the complete part number when ordering and quote this number in any future correspondence relating to your order.

CURRENT RATINGS

$T_{case} = 60^{\circ}\text{C}$ unless stated otherwise

Symbol	Parameter	Test Conditions	Max.	Units
Double Side Cooled				
$I_{T(AV)}$	Mean on-state current	Half wave resistive load	490	A
$I_{T(RMS)}$	RMS value	-	770	A
I_T	Continuous (direct) on-state current	-	730	A

SURGE RATINGS

Symbol	Parameter	Test Conditions	Max.	Units
I_{TSM}	Surge (non-repetitive) on-state current	10ms half sine, $T_{case} = 125^{\circ}\text{C}$	6.6	kA
I^2t	I^2t for fusing	$V_R = 0$	0.22	MA^2s

THERMAL AND MECHANICAL RATINGS

Symbol	Parameter	Test Conditions		Min.	Max.	Units
$R_{th(j-c)}$	Thermal resistance – junction to case	Double side cooled	DC	-	0.0379	$^{\circ}\text{C/W}$
		Single side cooled	Anode DC	-	0.0745	$^{\circ}\text{C/W}$
			Cathode DC	-	0.0797	$^{\circ}\text{C/W}$
$R_{th(c-h)}$	Thermal resistance – case to heatsink	Clamping force 11.5kN (with mounting compound)	Double side	-	0.0072	$^{\circ}\text{C/W}$
			Single side	-	.0144	$^{\circ}\text{C/W}$
T_{vj}	Virtual junction temperature	On-state (conducting)		-	135	$^{\circ}\text{C}$
		Reverse (blocking)		-	125	$^{\circ}\text{C}$
T_{stg}	Storage temperature range			-55	125	$^{\circ}\text{C}$
F_m	Clamping force			10	13	kN

DYNAMIC CHARACTERISTICS

Symbol	Parameter	Test Conditions		Min.	Max.	Units
I _{RRM} /I _{DRM}	Peak reverse and off-state current	At V _{RRM} /V _{DRM} , T _{case} = 125 °C		-	100	mA
dV/dt	Max. linear rate of rise of off-state voltage	To 67% V _{DRM} , T _j = 125 °C, gate open		-	1500	V/μs
dI/dt	Rate of rise of on-state current	From 67% V _{DRM} to 2x I _{T(AV)} Gate source 30V, 10Ω, t _r < 0.5μs, T _j = 125 °C	Repetitive 50Hz	-	100	A/μs
			Non-repetitive	-	200	A/μs
V _{T(TO)}	Threshold voltage – Low level	50A to 400A at T _{case} = 125 °C		-	0.912	V
	Threshold voltage – High level	400A to 1600A at T _{case} = 125 °C		-	1.108	V
r _T	On-state slope resistance – Low level	50A to 400A at T _{case} = 125 °C		-	2.157	mΩ
	On-state slope resistance – High level	400A to 1600A at T _{case} = 125 °C		-	1.647	mΩ
t _{gd}	Delay time	V _D = 67% V _{DRM} , gate source 30V, 10Ω t _r = 0.5μs, T _j = 25 °C		-	3	μs
t _q	Turn-off time	IT = 500A, T _j = 125 °C, V _R = 100V, dI/dt = 5A/μs, dV _{DR} /dt = 20V/μs linear		550	1100	μs
Q _S	Stored charge	I _T = 500A, T _j = 125 °C, dI/dt = 5A/μs,		1800	2600	μC
I _{RR}	Reverse recovery current	I _T = 500A, T _j = 125 °C, dI/dt = 5A/μs,		77	90	A
I _L	Latching current	T _j = 25 °C, V _D = 5V		-	3	A
I _H	Holding current	T _j = 25 °C, R _{G-K} = ∞, I _{TM} = 500A, I _T = 5A		-	300	mA

GATE TRIGGER CHARACTERISTICS AND RATINGS

Symbol	Parameter	Test Conditions	Max.	Units
V_{GT}	Gate trigger voltage	$V_{DRM} = 5V, T_{case} = 25^{\circ}C$	1.5	V
V_{GD}	Gate non-trigger voltage	At 50% $V_{DRM}, T_{case} = 125^{\circ}C$	0.4	V
I_{GT}	Gate trigger current	$V_{DRM} = 5V, T_{case} = 25^{\circ}C$	250	mA
I_{GD}	Gate non-trigger current	At 50% $V_{DRM}, T_{case} = 125^{\circ}C$	15	mA

CURVES

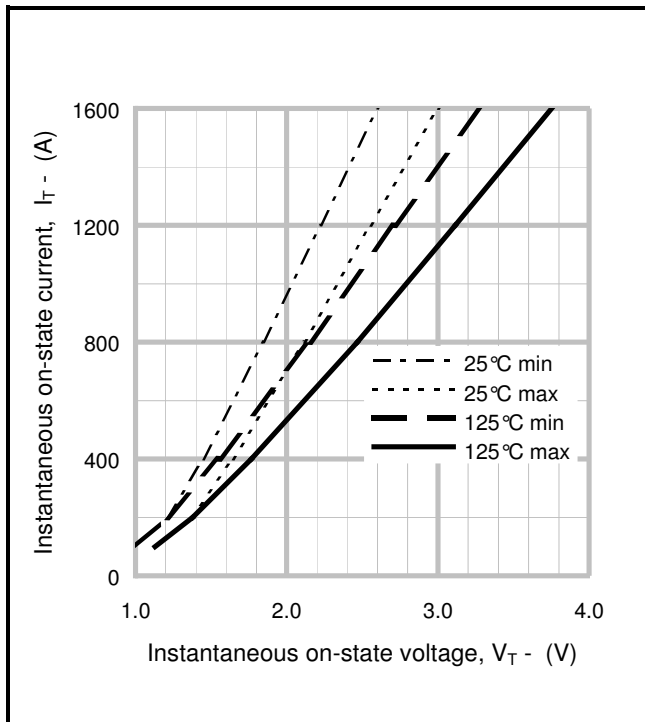


Fig.2 Maximum & minimum on-state characteristics

V_{TM} EQUATION

$$V_{TM} = A + B \ln(I_T) + C \cdot I_T + D \cdot \sqrt{I_T}$$

Where $A = 0.542452$
 $B = 0.065613$
 $C = 0.001318$
 $D = 0.015356$

these values are valid for $T_j = 125^{\circ}C$ for I_T 50A to 1600A

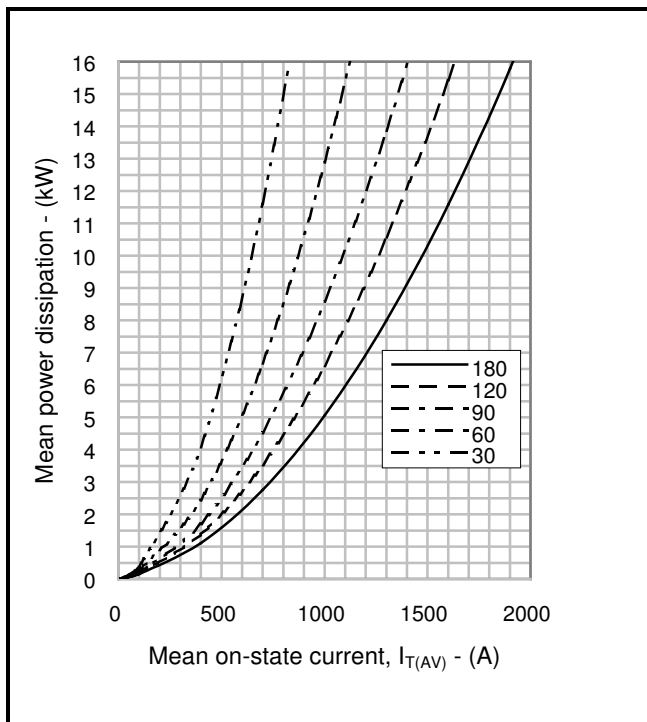


Fig.3 On-state power dissipation – sine wave

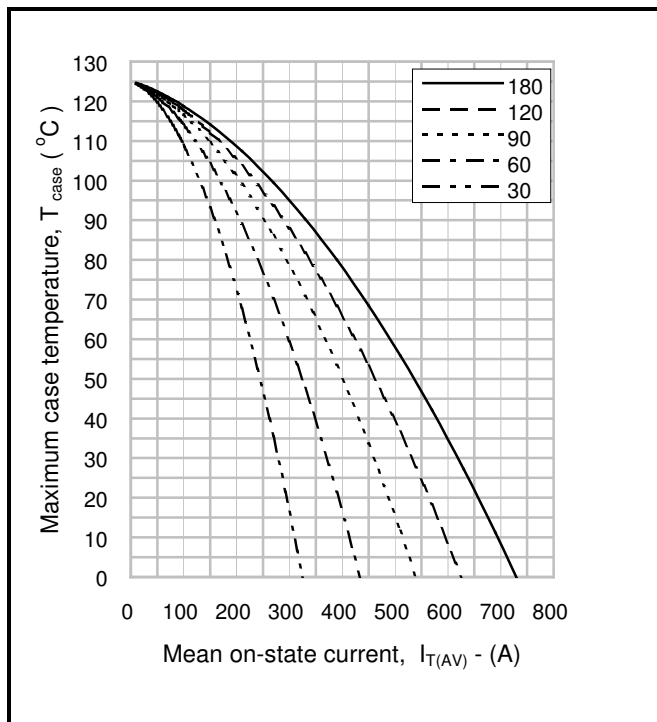


Fig.4 Maximum permissible case temperature, double side cooled – sine wave

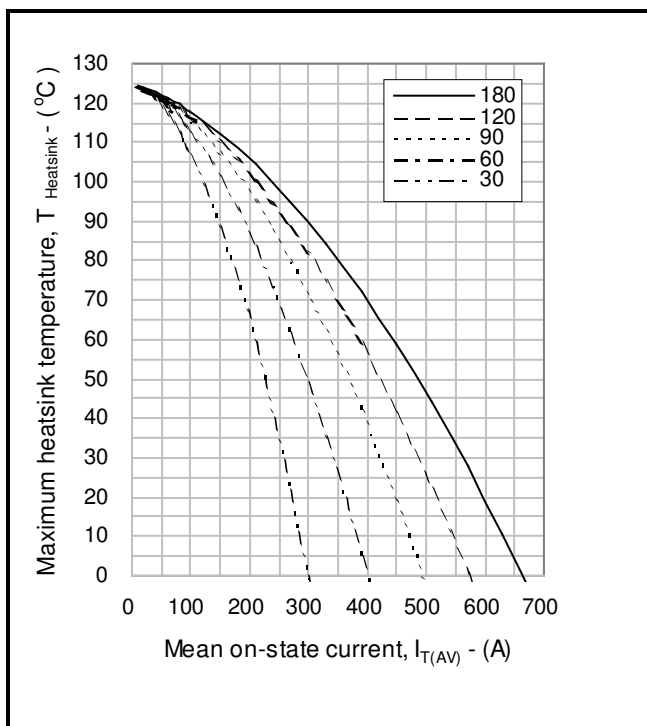


Fig.5 Maximum permissible heatsink temperature, double side cooled – sine wave

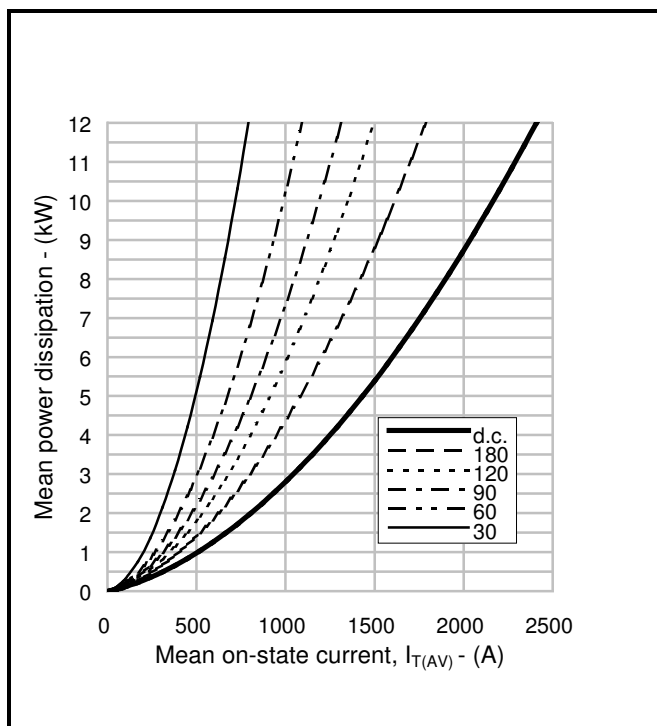


Fig.6 On-state power dissipation – rectangular wave

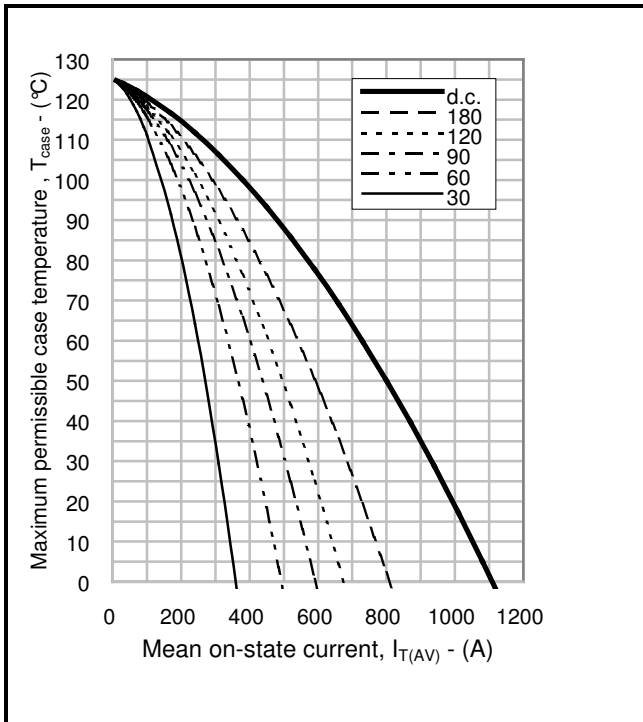


Fig.7 Maximum permissible case temperature, double side cooled – rectangular wave

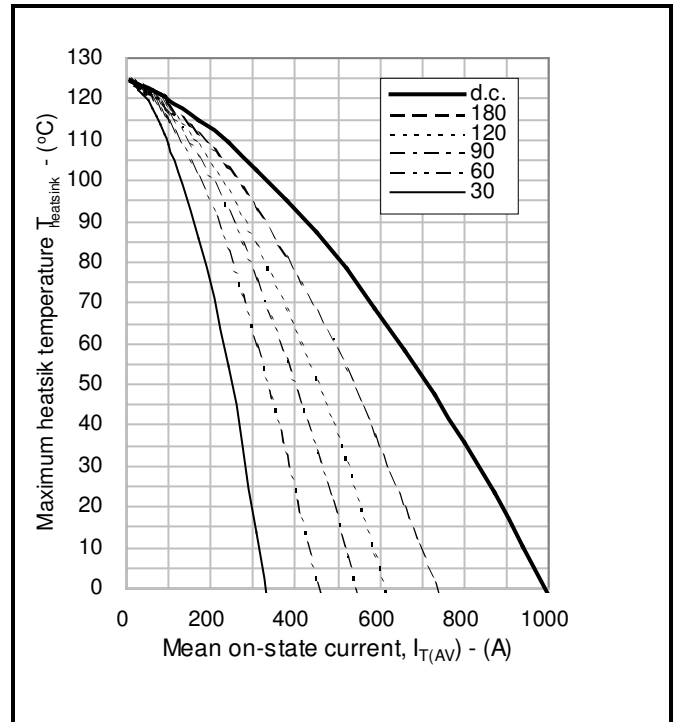


Fig.8 Maximum permissible heatsink temperature, double side cooled – rectangular wave

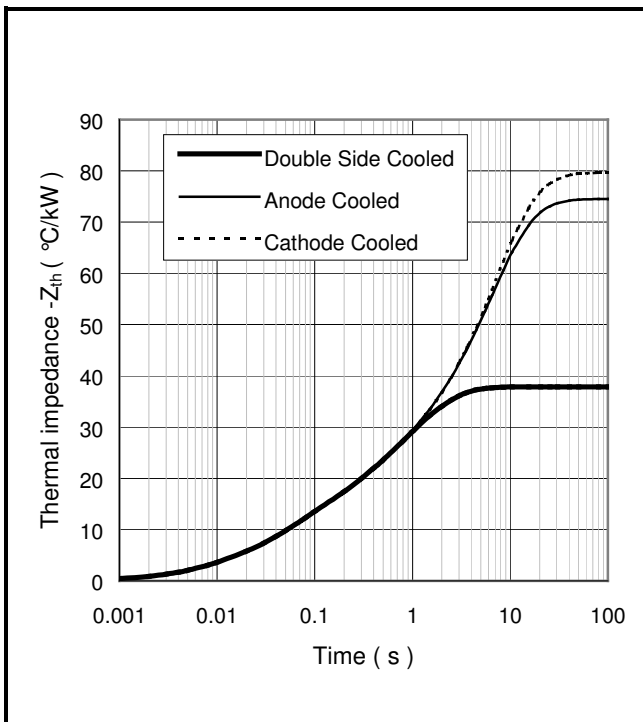


Fig.9 Maximum (limit) transient thermal impedance – junction to case (°C/kW)

		1	2	3	4
Double side cooled	R_{th} (°C/kW)	2.4256	9.3503	10.6963	15.3758
	T_1 (s)	0.0087759	0.053099	0.4497246	1.395
Anode side cooled	R_{th} (°C/kW)	2.8091	9.5576	11.3564	50.6136
	T_1 (s)	0.0097443	0.0591913	0.4759179	6.5548
Cathode side cooled	R_{th} (°C/kW)	2.9507	9.4031	11.0771	56.0405
	T_1 (s)	0.0100391	0.0606056	0.4732916	7.228

$$Z_{th} = \sum [R_{th} \times (1 - \exp(-t/t_1))] \quad [1]$$

$\Delta R_{th(j-c)}$ Conduction

Tables show the increments of thermal resistance $R_{th(j-c)}$ when the device operates at conduction angles other than d.c.

Double side cooling			Anode Side Cooling			Cathode Sided Cooling		
θ °	$\Delta Z_{th} (z)$		θ °	$\Delta Z_{th} (z)$		θ °	$\Delta Z_{th} (z)$	
	sine.	rect.		sine.	rect.		sine.	rect.
180	4.43	3.01	180	4.39	2.99	180	4.37	2.98
120	5.13	4.30	120	5.07	4.26	120	5.05	4.25
90	5.89	5.03	90	5.81	4.97	90	5.79	4.96
60	6.58	5.81	60	6.48	5.74	60	6.45	5.72
30	7.12	6.67	30	7.00	6.57	30	6.97	6.54
15	7.36	7.13	15	7.24	7.01	15	7.20	6.98

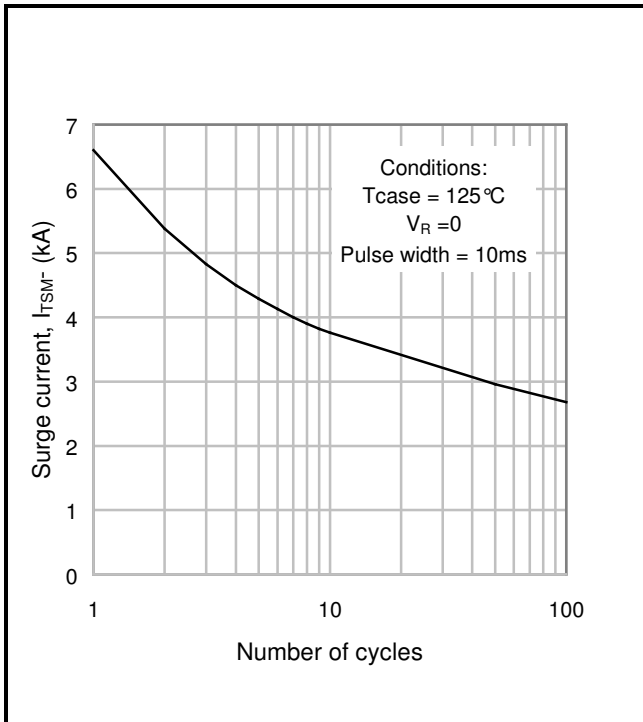


Fig.10 Multi-cycle surge current

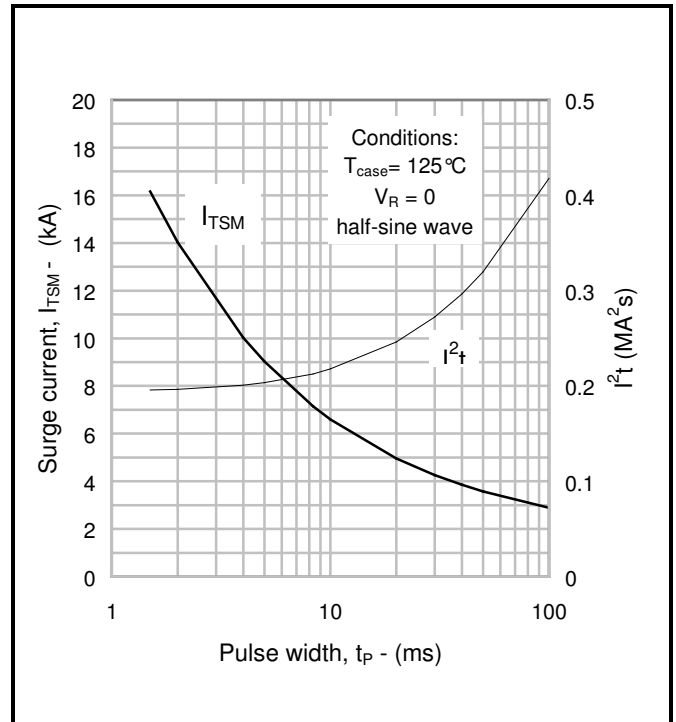


Fig.11 Single-cycle surge current

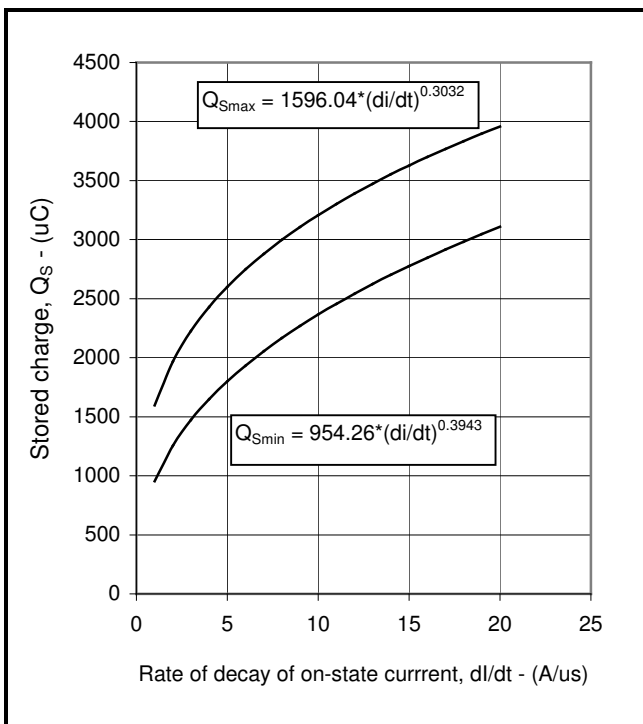


Fig.12 Stored charge vs di/dt

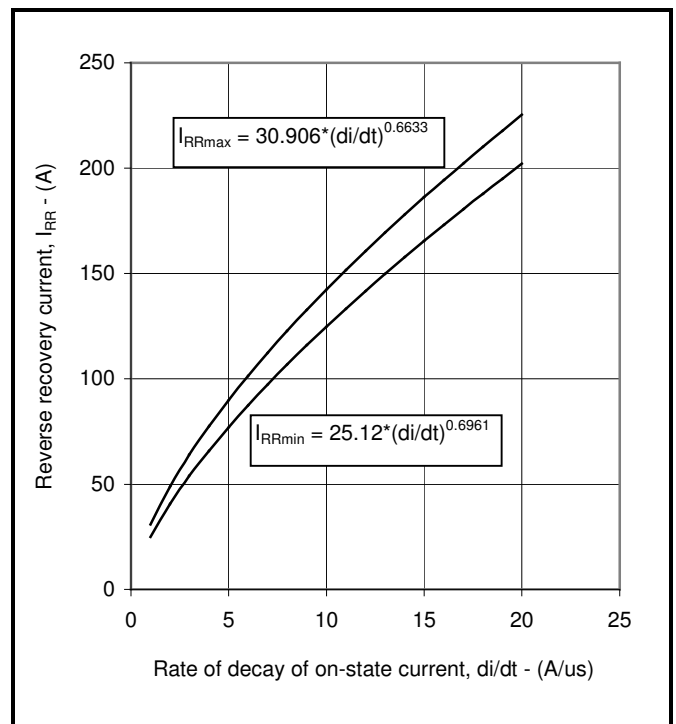


Fig.13 Reverse recovery current vs di/dt

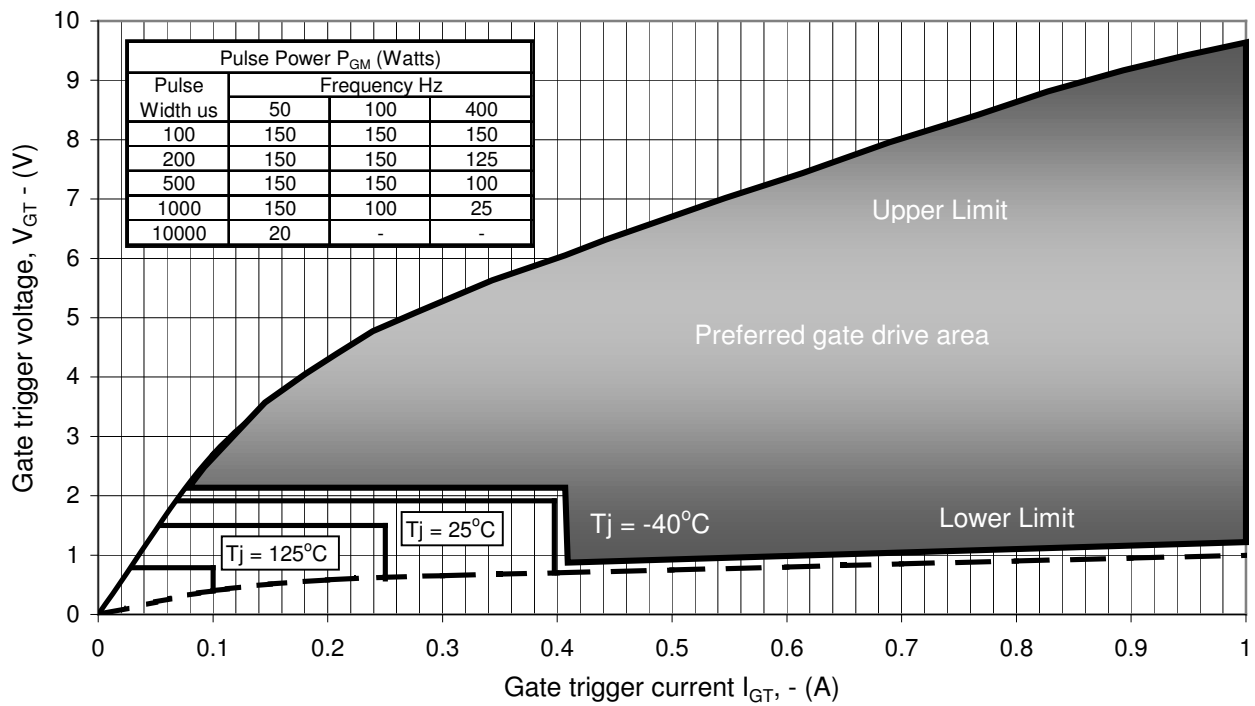


Fig14 Gate Characteristics

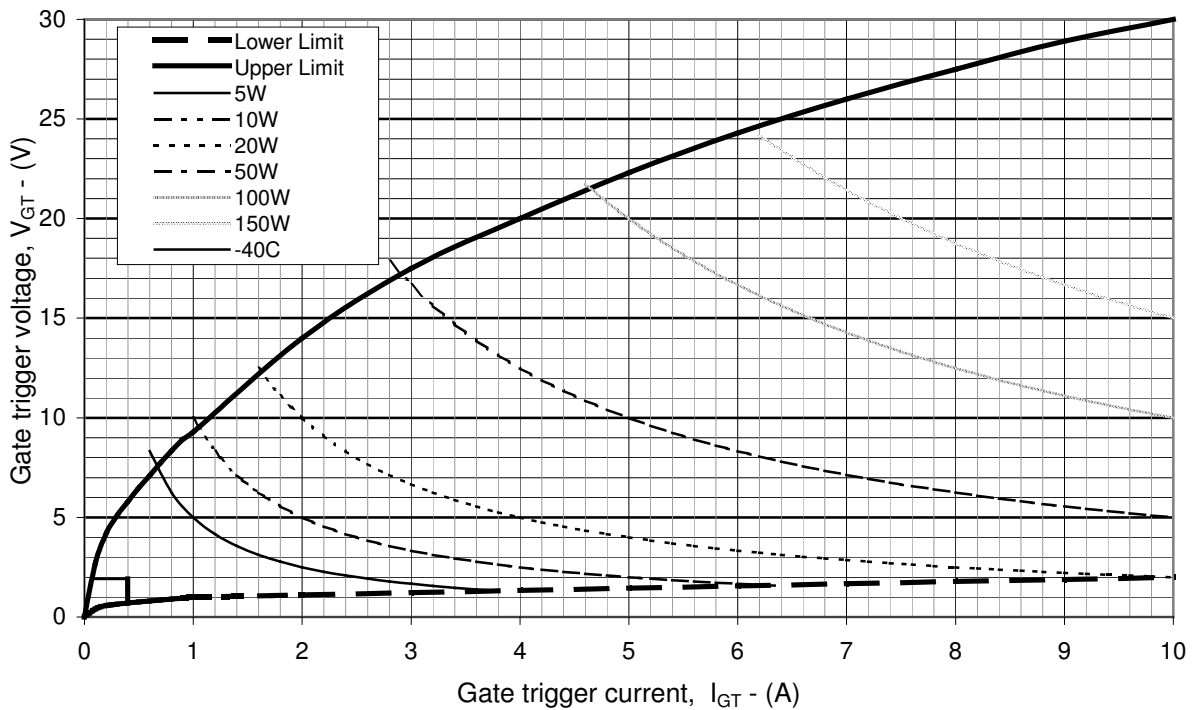

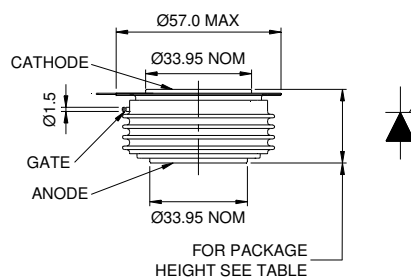
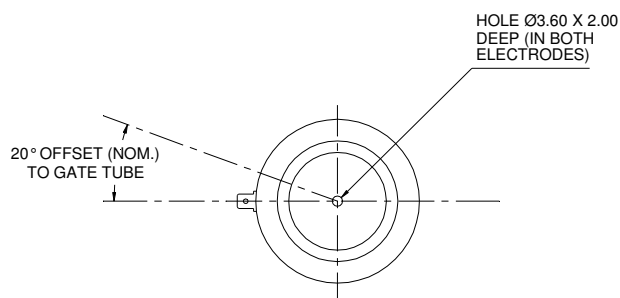


Fig. 15 Gate characteristics

PACKAGE DETAILS

For further package information, please contact Customer Services. All dimensions in mm, unless stated otherwise. DO NOT SCALE.

3rd ANGLE PROJECTION  DO NOT SCALE IF IN DOUBT ASK



Device	Maximum Thickness (mm)	Minimum Thickness (mm)
DCR880J22	34.465	33.915
DCR780J28	34.54	33.99
DCR640J42	34.77	34.22
DCR570J52	34.89	34.34
DCR490J65	35.15	34.6
DCR390J85	35.51	34.96

Clamping force: 11.5 kN $\pm 10\%$
Lead length: 420mm
Lead terminal connector: M4 ring

Package outline type code: J

Fig.16 Package outline

POWER ASSEMBLY CAPABILITY

The Power Assembly group was set up to provide a support service for those customers requiring more than the basic semiconductor, and has developed a flexible range of heatsink and clamping systems in line with advances in device voltages and current capability of our semiconductors.

We offer an extensive range of air and liquid cooled assemblies covering the full range of circuit designs in general use today. The Assembly group offers high quality engineering support dedicated to designing new units to satisfy the growing needs of our customers.

Using the latest CAD methods our team of design and applications engineers aim to provide the Power Assembly Complete Solution (PACs).

HEATSINKS

The Power Assembly group has its own proprietary range of extruded aluminium heatsinks which have been designed to optimise the performance of Dynex semiconductors. Data with respect to air natural, forced air and liquid cooling (with flow rates) is available on request.

For further information on device clamps, heatsinks and assemblies, please contact your nearest sales representative or Customer Services.

Stresses above those listed in this data sheet may cause permanent damage to the device. In extreme conditions, as with all semiconductors, this may include potentially hazardous rupture of the package. Appropriate safety precautions should always be followed.



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ERROR: syntaxerror
OFFENDING COMMAND: --nostringval--
OPERAND STACK: